

L Number	Hits	Search Text	DB	Time stamp
1	113	(memory and test\$3 and defect\$3 and repair\$3) and ((buffer latch register) with (data information) with defect\$3) and controller and (data with stor\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/11 20:07
2	2625656	1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/11 20:07
3	11	((memory and test\$3 and defect\$3 and repair\$3) and ((buffer latch register) with (data information) with defect\$3) and controller and (data with stor\$3)) and (defect\$3 same (temp\$7 near3 (stor\$3 buffer data)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/11 20:21
4	7	((memory and test\$3 and defect\$3 and repair\$3) and ((buffer latch register) with (data information) with defect\$3) and controller and (data with stor\$3)) and (defect\$3 with temp\$7 with stor\$3 with (data information))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/11 20:14
-	24	memory and test\$3 and defect\$3 and repair\$3 and (alternat\$3 near3 (row column)) and address and (fail\$3 fault\$1) and (mov\$3 near3 data)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 13:52
-	5812	memory and test\$3 and defect\$3 and repair\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/11 16:51
-	0	(memory and test\$3 and defect\$3 and repair\$3) and ((temp\$3 near3 (stor\$3 buffer)) with data)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 13:54
-	641	(temp\$3 near3 (stor\$3 buffer)) with data	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 13:54
-	0	(memory and test\$3 and defect\$3 and repair\$3) and (temp\$3 with (stor\$3 buffer) with data)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 13:54
-	291	(memory and test\$3 and defect\$3 and repair\$3) and (test\$3 with defect\$3) and (repair\$3 with (row column) with (address data))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 13:56
-	24	((memory and test\$3 and defect\$3 and repair\$3) and (test\$3 with defect\$3) and (repair\$3 with (row column) with (address data))) and (temp\$7 with (stor\$3 buffer))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 16:30
-	21	((memory and test\$3 and defect\$3 and repair\$3) and (test\$3 with defect\$3) and (repair\$3 with (row column) with (address data))) and ((alternat\$3 adj2 (row column)) (every adj2 other adj2 (row column)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 14:05
-	26	"L24" and (mov\$3 near3 data)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 16:30

-	2	((memory and test\$3 and defect\$3 and repair\$3) and (test\$3 with defect\$3) and (repair\$3 with (row column) with (address data))) and (temp\$7 with (stor\$3 buffer)) and (mov\$3 near3 data)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 17:56
-	1527	detect\$3 near4 defect\$3 near4 (cell transistor)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 17:56
-	400	test with (detect\$3 near4 defect\$3 near4 (cell transistor))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 17:57
-	508	test\$3 with (detect\$3 near4 defect\$3 near4 (cell transistor))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 17:57
-	20	(test\$3 with (detect\$3 near4 defect\$3 near4 (cell transistor))) and (repair\$3 with (mov\$3 replac\$3 exchang\$3) with data)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 17:58
-	20	(test\$3 with (detect\$3 near4 defect\$3 near4 (cell transistor))) and (repair\$3 with (mov\$3 replac\$3 exchang\$3 rearrang\$3 re-arrang\$3) with data)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 17:58